

Search Notes

Application/Control No.

10/602,393

Examiner

Jung Park

Applicant(s)/Patent under
Reexamination

STEPHENS, ADRIAN P.

Art Unit

2616

SEARCHED

Class	Subclass	Date	Examiner

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
370/338, 328, 229, 230, 230.1, 235 (text search only - see history printout)	3/15/2007	JP
Text search in EAST (USPT, PGPUB) - see history printout	3/15/2007	JP
Internet search for IEEE standard	3/16/2007	JP
Above 370/ UPDATED	8/22/2007	JP